

Holistic IJTAG-based external and internal fault monitoring in UAVs

Ahmed, Foisal; Jenihhin, Maksim arXiv.org 2023 / 6 p. : ill <https://doi.org/10.48550/arXiv.2303.01816>

On BTI aging rejuvenation in memory address decoders

Gürsoy, Cemil Cem; Kraak, Daniel; Ahmed, Foisal; Taouil, Mottaqiallah; Jenihhin, Maksim; Hamdioui, Said 2022 IEEE 23rd Latin American Test Symposium, LATS 2022 2022 / Code 184360 <https://doi.org/10.1109/LATS57337.2022.9936940>

Reliability-critical computation offloading in UAV swarms

Rahbari, Dadmehr; Ahmed, Foisal; Jenihhin, Maksim; Alam, Muhammad Mahtab; Le Moullec, Yannick IEEE Systems Journal 2024 / p. 1871-1882 <https://doi.org/10.1109/JSYST.2024.3432449> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

A survey on UAV computing platforms : a hardware reliability perspective

Ahmed, Foisal; Jenihhin, Maksim Sensors 2022 / art. 6286 <https://doi.org/10.3390/s22166286> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Systematic unsupervised recycled field-programmable gate array detection

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Unsupervised recycled FPGA detection using symmetry analysis

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